Notice of References Cited	Application/Control No. 10/678,642	Applicant(s)/Patent Under Reexamination OYAMA ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,922,878	05-1990	Shinogle et al.	123/490
	B	US-5,941,216 A	08-1999	Arakawa, Yoshinobu	123/490
	C	US-6,173,700 B1	01-2001	Yamashita et al.	123/490
	D	US-6,234,150 B1	05-2001	Watanabe, Tetsushi	123/490
	E	US-6,332,455 B1	12-2001	Sumida et al.	123/490
	F	US-6,431,155 B1	08-2002	Yamakado et al.	123/490
	G	US-6,453,876 B1	09-2002	Fukutomi et al.	123/490
	H	US-6,532,940 B1	03-2003	Ono et al.	123/490
	I	US-6,571,773 B1	06-2003	Yamakado et al.	123/490
	J	US-6,684,862 B2	02-2004	Oyama et al.	123/490
	K	US-6,712,048 B2	03-2004	Aoki et al.	123/490
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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